

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1302	Mar-97	9705 A3	ANAM, K.	DN646311ABA	0.8μ OX/NI (2 MTL)	08 SOIC 150

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-19075

<u>Electrical</u>	<u>Cum %</u>
235/0	0.0%

Infant / High Voltage Life
125°C, 6.0 V.
P-19146, P-19244

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
231/2	77/0	77/0	277 Fits
F1			

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-19245

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
39/0	39/0	0.0%

Biased Moisture (HAST)
120°C/85% RH, 5.5 V.
P-19246

<u>100 Hr</u>	<u>Cum %</u>
77/0	0.0%

Autoclave
121°C/100% RH, 2 Atoms
P-19247

<u>96 Hr</u>	<u>Cum %</u>
36/0	0.0%

Failure Mode

F1: 2-lcc

Failure Analysis

970056 - Leakage recovered during analysis.